

Device Modeling Report

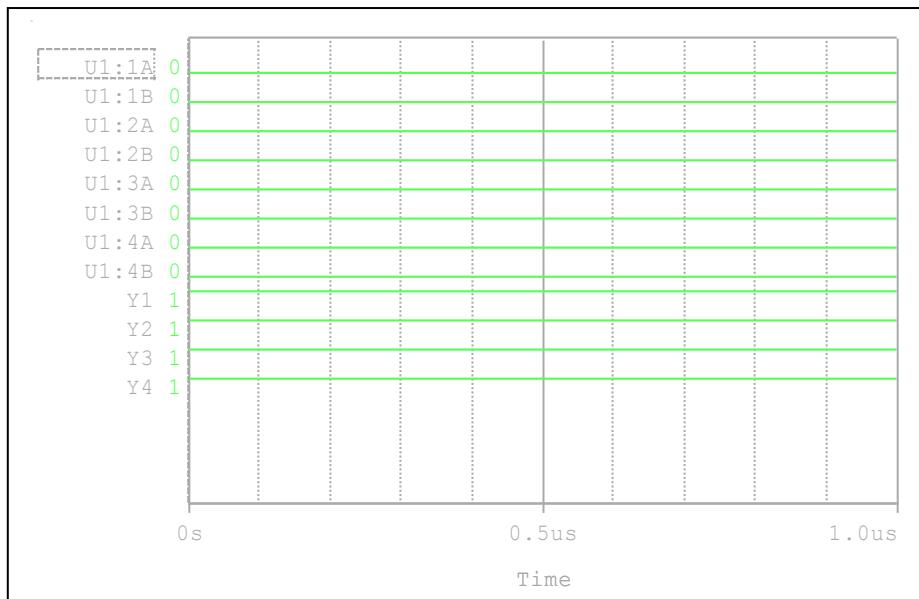
COMPONENTS : CMOS DIGITAL INTEGRATED CIRCUIT
PART NUMBER : TC74HC00AP
MANUFACTURER : TOSHIBA



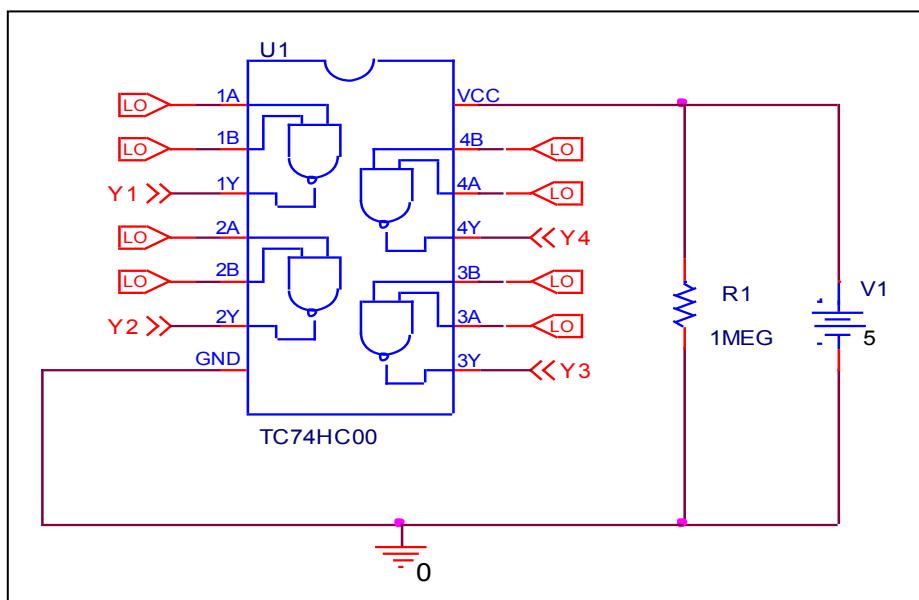
Bee Technologies Inc.

Truth Table

Circuit simulation result



Evaluation circuit

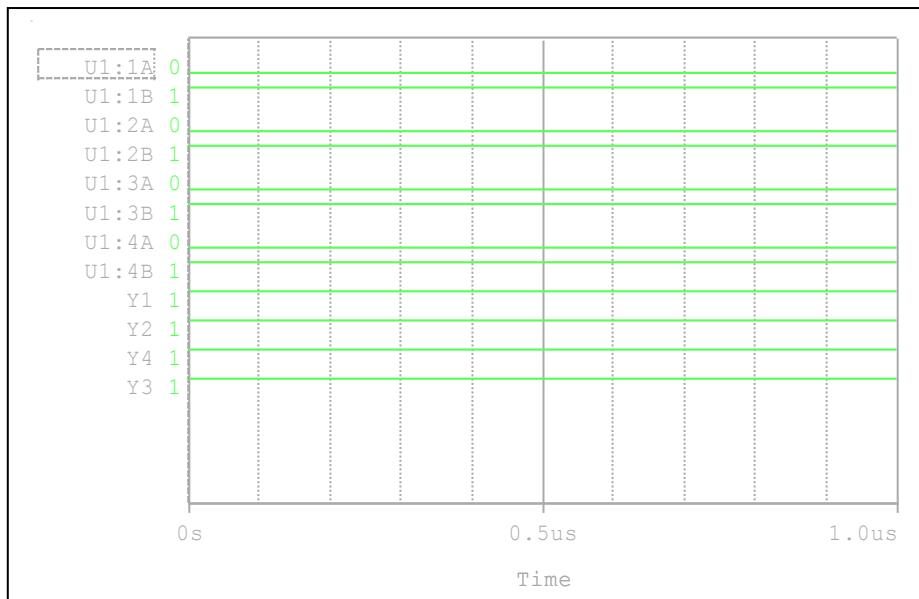


Comparison table

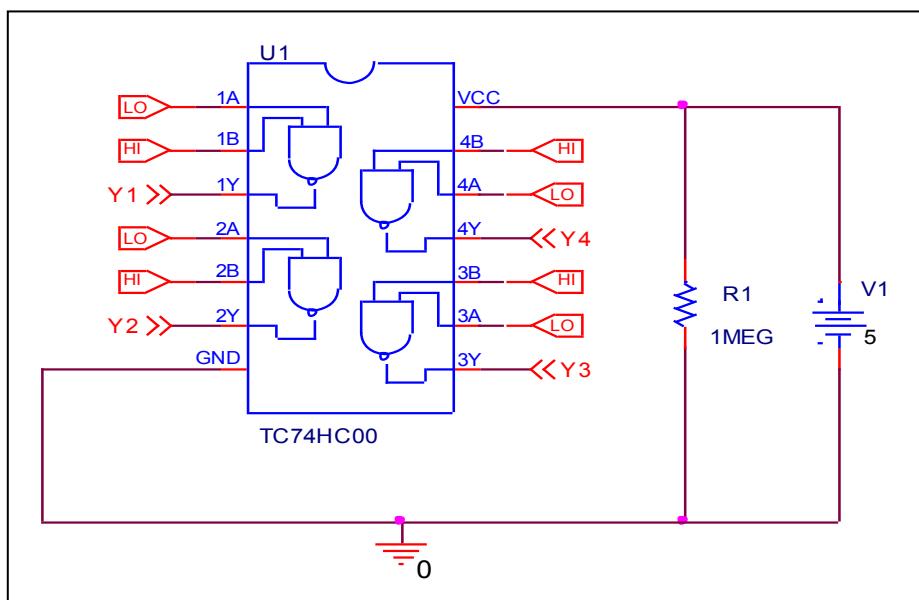
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
L	L	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

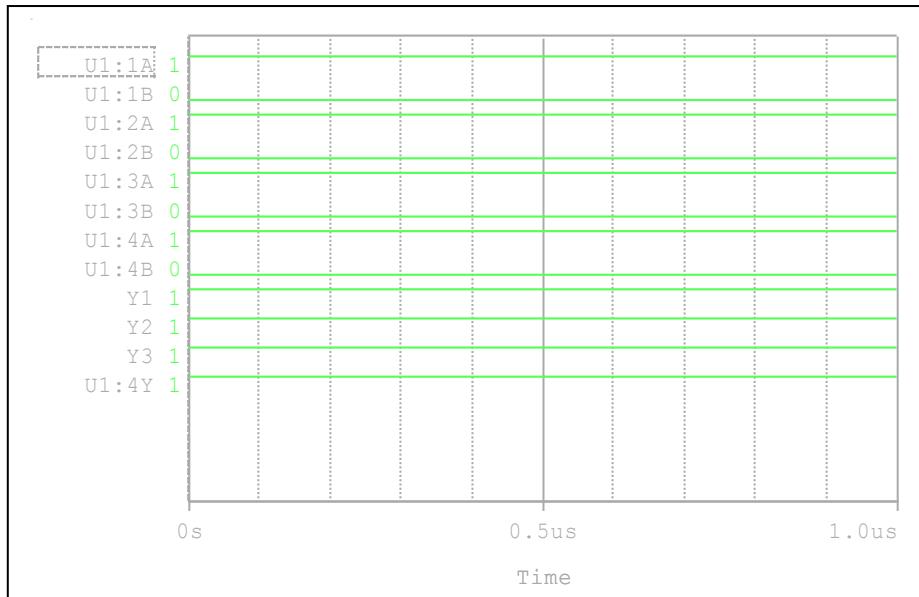


Comparison table

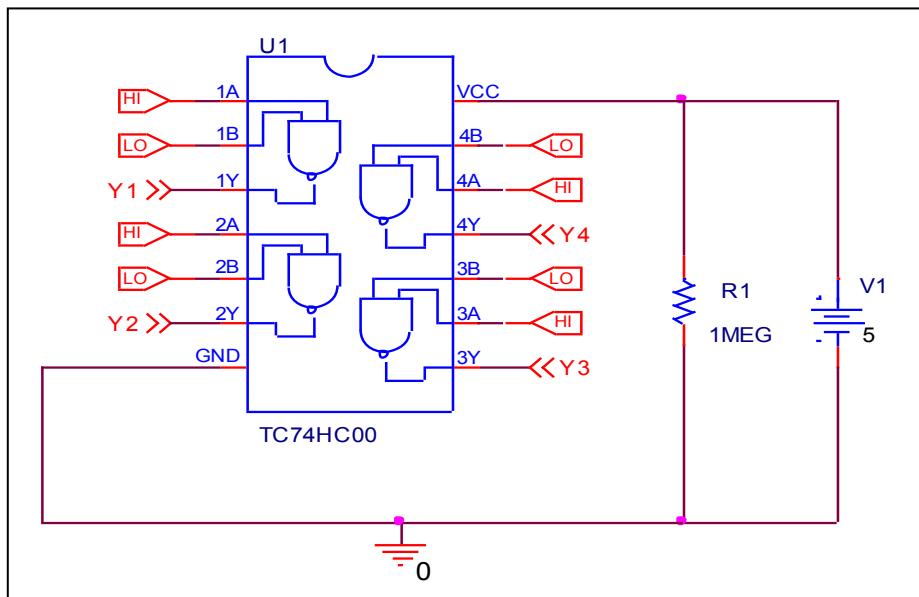
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
L	H	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

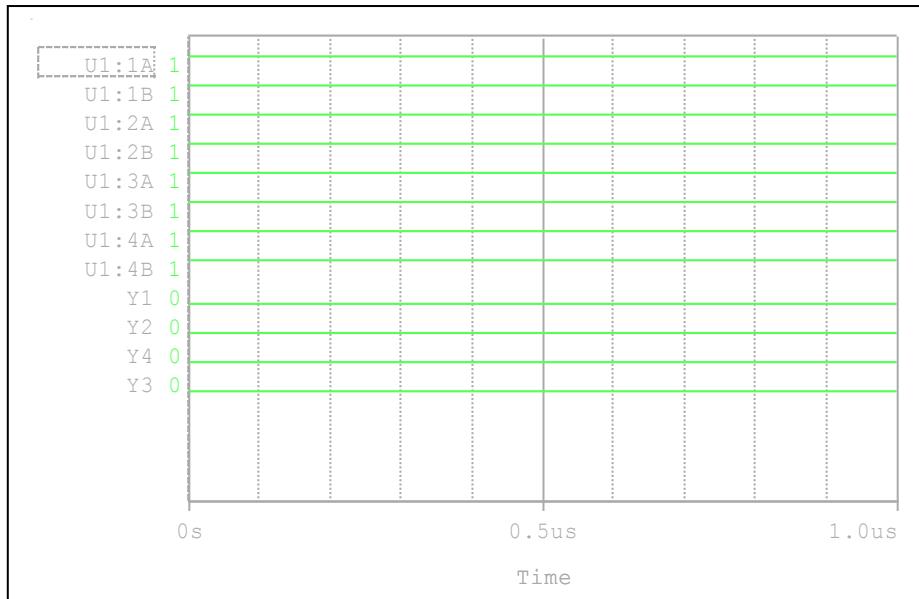


Comparison table

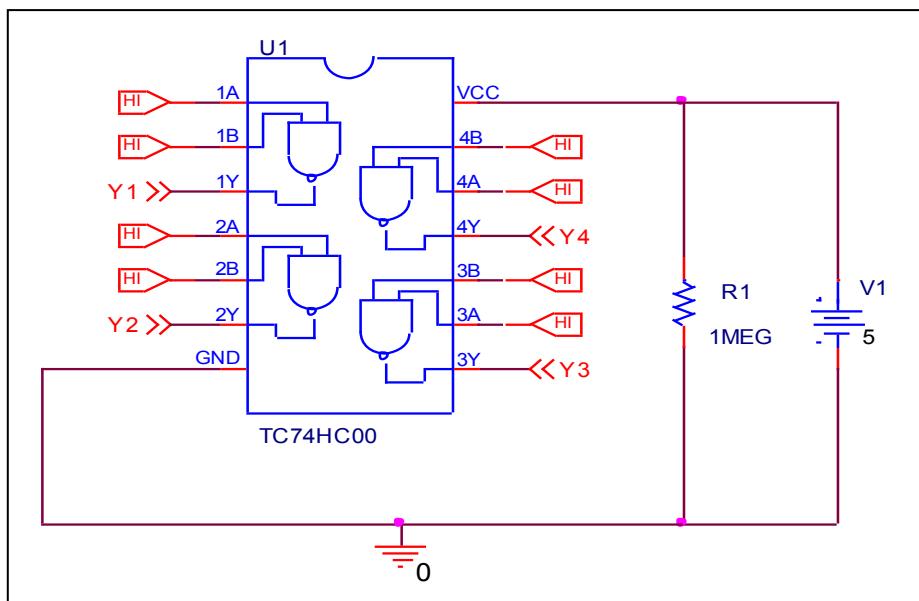
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
H	L	H	H	0

Truth Table

Circuit simulation result



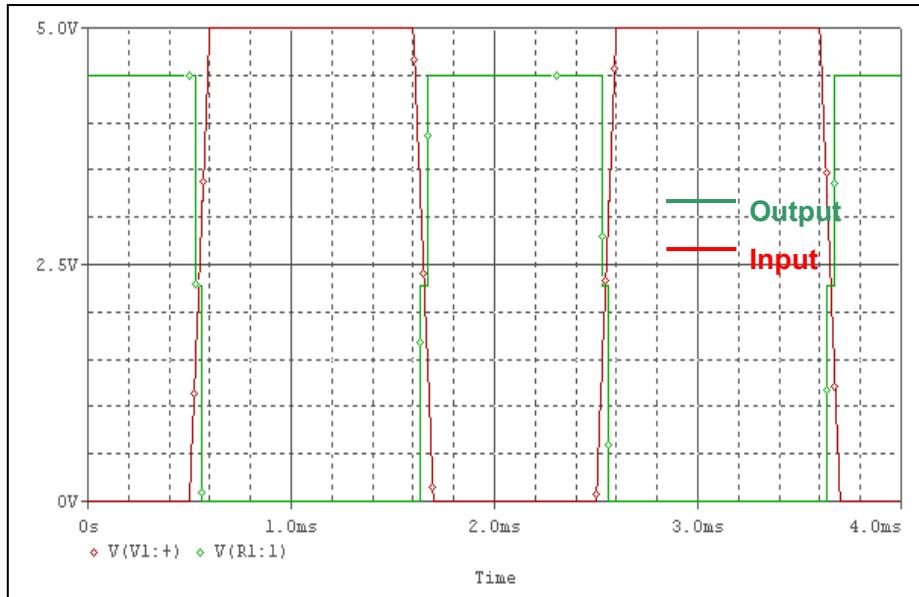
Evaluation circuit



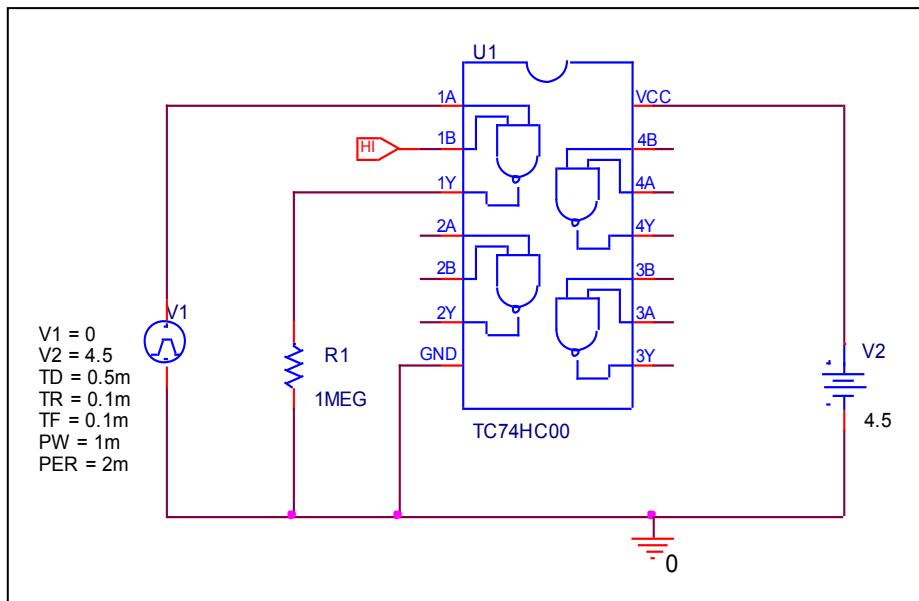
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
H	H	L	L	0

High Level and Low Level Input Voltage

Circuit simulation result



Evaluation circuit

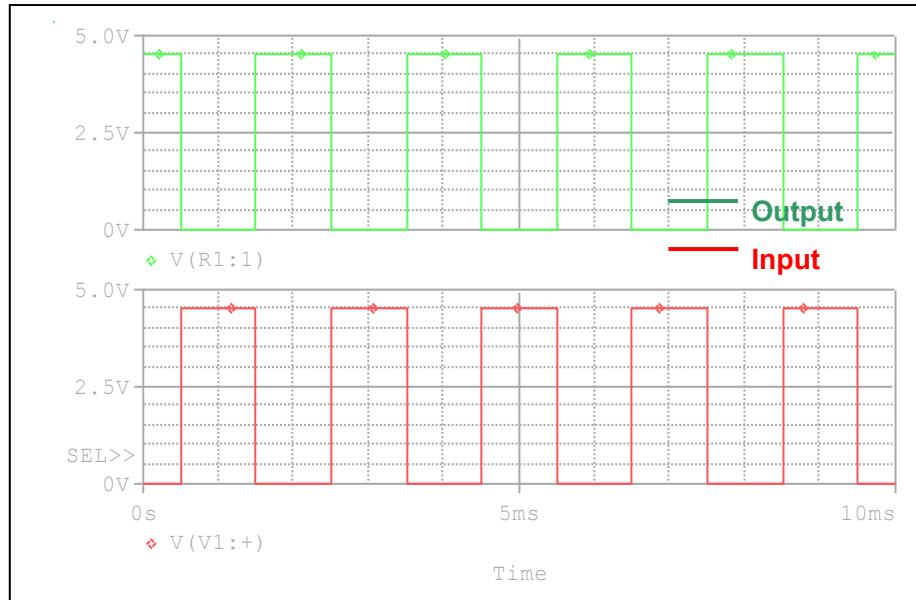


Comparison table

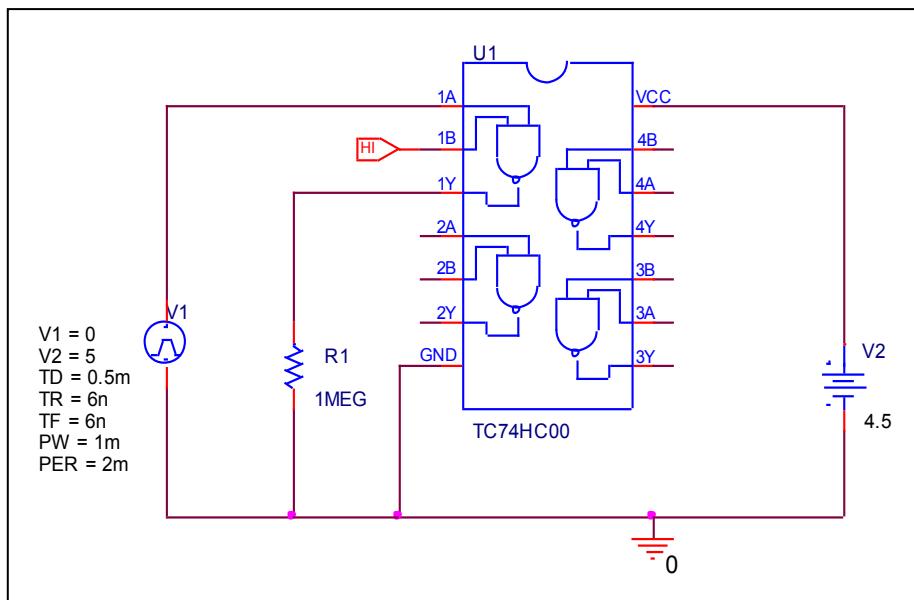
$V_{CC} = 4.5V$	Measurement	Simulation	%Error
$V_{IH} (V)$	3.15	3.1506	0.019
$V_{IL} (V)$	1.35	1.3456	-0.326

High Level and Low Level Output Voltage

Circuit simulation result



Evaluation circuit



Comparison table

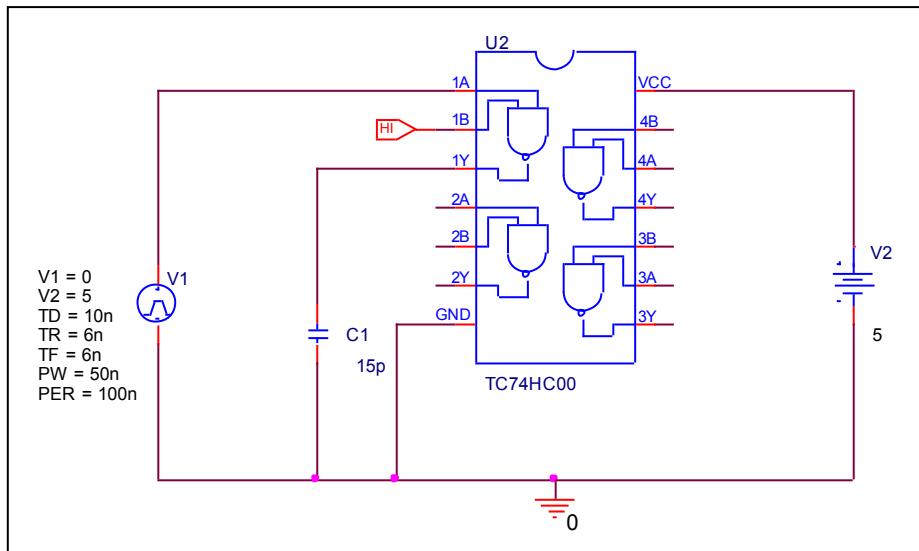
$V_{CC} = 4.5V$	Measurement	Simulation	%Error
$V_{OH}(V)$	4.5	4.4975	-0.056
$V_{OL}(V)$	0	0	0

Propagation Delay Time

Circuit simulation result



Evaluation circuit



Comparison table

$C_L = 15\text{pF}, V_{CC} = 5\text{V}, t_r = t_f = 6\text{ns}$	Measurement	Simulation	%Error
$t_{TLH} (\text{ns})$	4	4.0014	0.035
$t_{THL} (\text{ns})$	4	4.0168	0.420
$T_{pLH} (\text{ns})$	6	6.0591	0.985
$T_{pHL} (\text{ns})$	6	6.0419	0.698